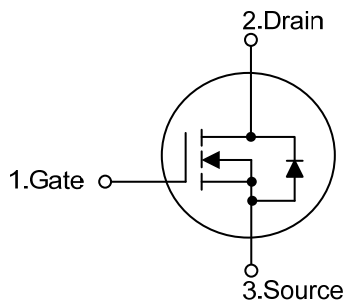


**8N80-FCQ****Power MOSFET****8A, 800V N-CHANNEL
POWER MOSFET****DESCRIPTION**

The UTC **8N80-FCQ** provide excellent $R_{DS(ON)}$, low gate charge and operation with low gate voltages. This device is suitable for use as a load switch or in PWM applications.

FEATURES

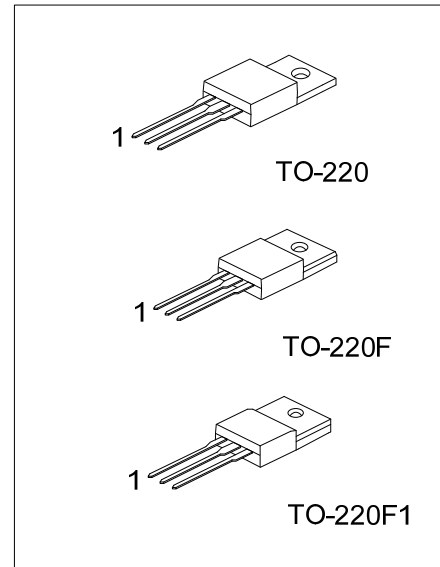
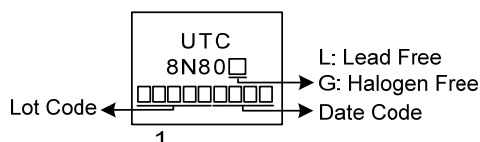
- * $R_{DS(ON)} \leq 1.62 \Omega$ @ $V_{GS}=10V$, $I_D=4.0A$
- * Fast switching capability
- * Avalanche energy specified
- * Improved dv/dt capability, high ruggedness

SYMBOL**ORDERING INFORMATION**

Ordering Number		Package	Pin Assignment			Packing
Lead Free	Halogen Free		1	2	3	
8N80L-TA3-T	8N80G-TA3-T	TO-220	G	D	S	Tube
8N80L-TF1-T	8N80G-TF1-T	TO-220F1	G	D	S	Tube
8N80L-TF3-T	8N80G-TF3-T	TO-220F	G	D	S	Tube

Note: Pin Assignment: G: Gate D: Drain S: Source

8N80G-TA3-T (1) Packing Type (2) Package Type (3) Green Package	(1) T: Tube (2) TA3: TO-220, TF1: TO220F1, TF3: TO-220F (3) G: Halogen Free and Lead Free, L: Lead Free
---	--

MARKING

■ **ABSOLUTE MAXIMUM RATINGS** ($T_C=25^{\circ}\text{C}$, unless otherwise specified)

PARAMETER		SYMBOL	RATINGS	UNIT
Drain-Source Voltage		V_{DS}	800	V
Gate-Source Voltage		V_{GS}	± 30	V
Continuous Drain Current		I_D	8	A
Pulsed Drain Current (Note 2)		I_{DM}	16	A
Avalanche Energy (Note 3)	Single Pulsed	E_{AS}	61.3	mJ
Peak Diode Recovery dv/dt (Note 4)		dv/dt	2.2	V/ns
Power Dissipation ($T_A=25^{\circ}\text{C}$)	TO-220	P_D	140	W
	TO-220F/TO-220F1		35	W
Junction Temperature		T_J	+150	$^{\circ}\text{C}$
Storage Temperature		T_{STG}	-55 ~ +150	$^{\circ}\text{C}$

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged.

Absolute maximum ratings are stress ratings only and functional device operation is not implied.

2. Repetitive Rating: Pulse width limited by maximum junction temperature.

3. $L=10\text{mH}$, $I_{AS}=3.5\text{A}$, $V_{DD}=50\text{V}$, $R_G=25\ \Omega$, Starting $T_J = 25^{\circ}\text{C}$

4. $I_{SD}\leq 8.0\text{A}$, $di/dt\leq 200\text{A}/\mu\text{s}$, $V_{DD}\leq BV_{DSS}$, Starting $T_J = 25^{\circ}\text{C}$

■ **THERMAL DATA**

PARAMETER		SYMBOL	RATING	UNIT
Junction to Ambient		θ_{JA}	62.5	$^{\circ}\text{C}/\text{W}$
Junction to Case	TO-220	θ_{JC}	1.12	$^{\circ}\text{C}/\text{W}$
	TO-220F/TO-220F1		3.57	$^{\circ}\text{C}/\text{W}$

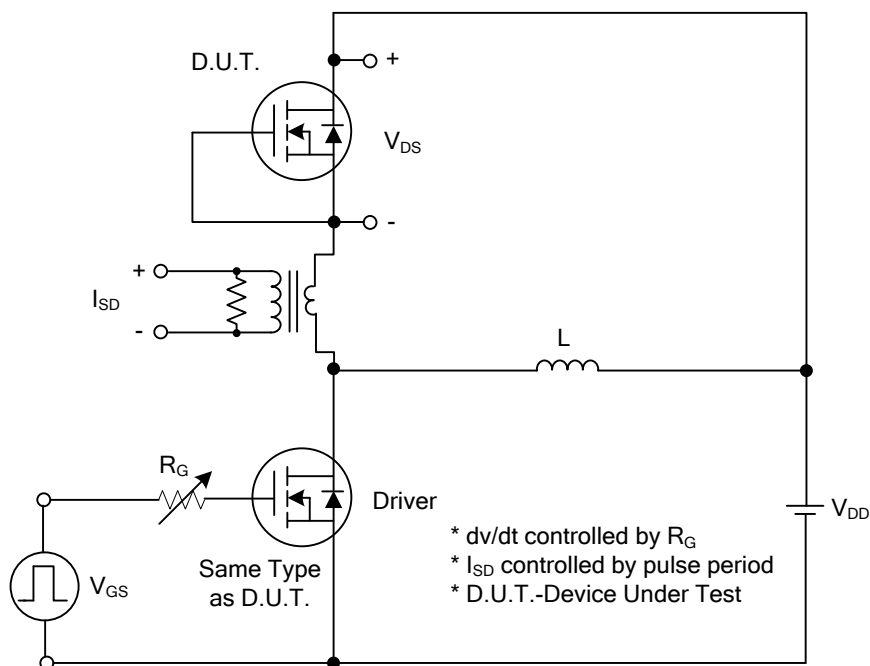
■ **ELECTRICAL CHARACTERISTICS** ($T_J=25^{\circ}\text{C}$, unless otherwise specified)

PARAMETER		SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
OFF CHARACTERISTICS							
Drain-Source Breakdown Voltage		BV _{DSS}	V _{GS} = 0V, I _D = 250μA	800			V
Drain-Source Leakage Current		I _{DSS}	V _{DS} = 800V, V _{GS} = 0V			10	μA
Gate-Source Leakage Current	Forward	I _{GSS}	V _{GS} = 30V, V _{DS} = 0V			100	nA
	Reverse		V _{GS} = -30V, V _{DS} = 0V			-100	nA
ON CHARACTERISTICS							
Gate Threshold Voltage		V _{GS(TH)}	V _{DS} = V _{GS} , I _D = 250μA	3.0		5.0	V
Static Drain-Source On-State Resistance		R _{DS(ON)}	V _{GS} = 10V, I _D =4.0A			1.62	Ω
DYNAMIC CHARACTERISTICS							
Input Capacitance		C _{ISS}	V _{DS} =25V, V _{GS} =0V, f =1MHz		1130		pF
Output Capacitance		C _{OSS}			117		pF
Reverse Transfer Capacitance		C _{RSS}			2.4		pF
SWITCHING CHARACTERISTICS							
Total Gate Charge		Q _G	V _{DS} =640V, V _{GS} =10V, I _D =8A, I _G =1mA (Note 1, 2)		22.8		nC
Gate-Source Charge		Q _{GS}			8.8		nC
Gate-Drain Charge		Q _{GD}			3		nC
Turn-On Delay Time		t _{D(ON)}	V _{DD} =100V, V _{GS} =10V, I _D =8A, R _G =25Ω (Note 1, 2)		12.6		ns
Turn-On Rise Time		t _R			16.5		ns
Turn-Off Delay Time		t _{D(OFF)}			49		ns
Turn-Off Fall Time		t _F			34		ns
DRAIN-SOURCE DIODE CHARACTERISTICS							
Maximum Body-Diode Continuous Current		I _S				8	A
Continuous Drain-Source Current		I _{SD}				16	A
Drain-Source Diode Forward Voltage		V _{SD}	I _S =8A, V _{GS} =0V			1.4	V
Reverse Recovery Time		t _{rr}	I _F =8A, di/dt = 100A/μs		530		ns
Reverse Recovery Charge		Q _{rr}			6		μC

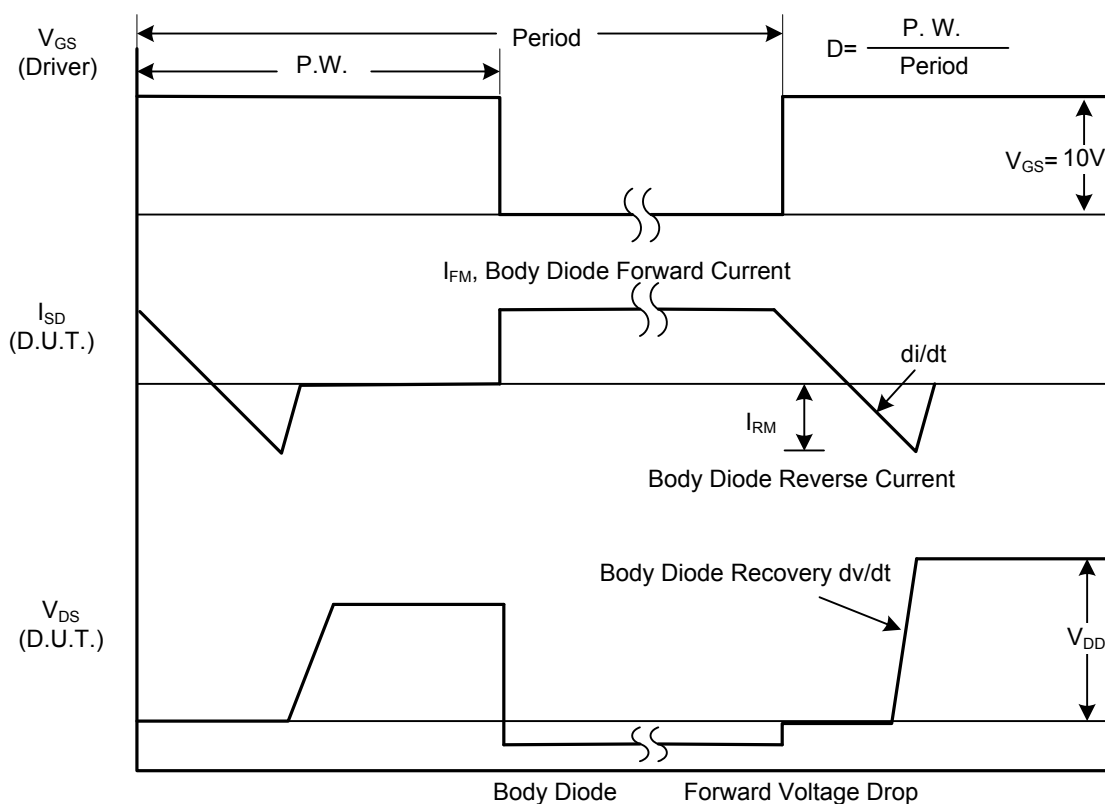
Notes: 1. Pulse Test: Pulse width $\leq 300\mu s$, Duty cycle $\leq 2\%$.

2. Essentially independent of operating temperature.

■ TEST CIRCUITS AND WAVEFORMS

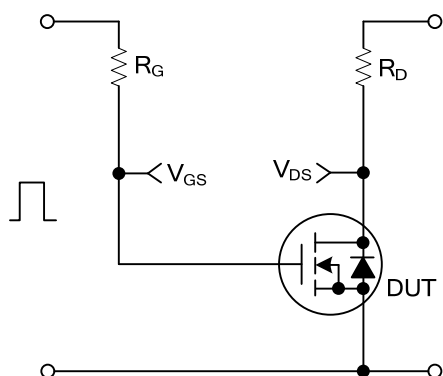


Peak Diode Recovery dv/dt Test Circuit

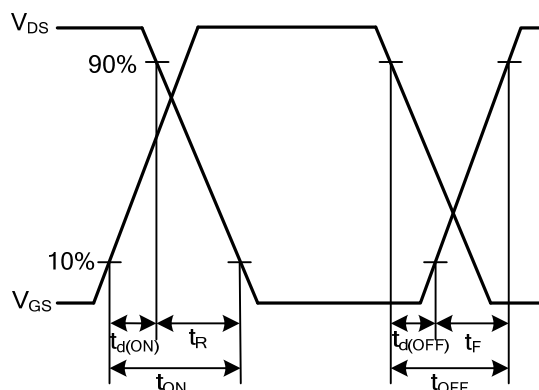


Peak Diode Recovery dv/dt Waveforms

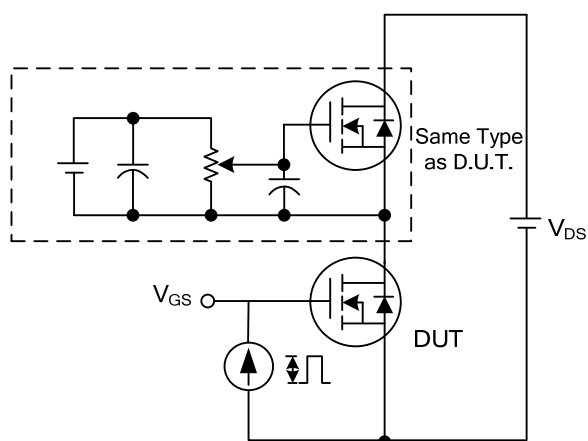
■ TEST CIRCUITS AND WAVEFORMS



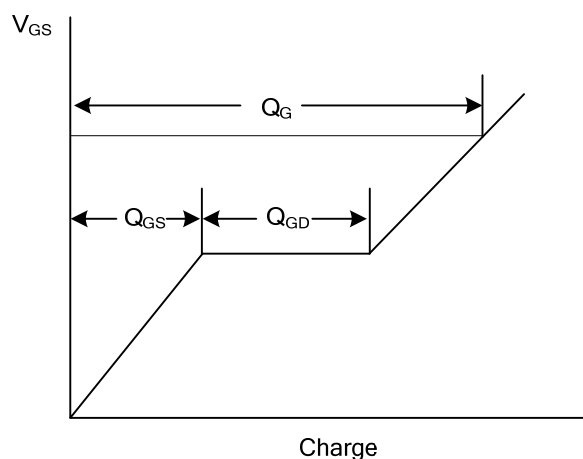
Switching Test Circuit



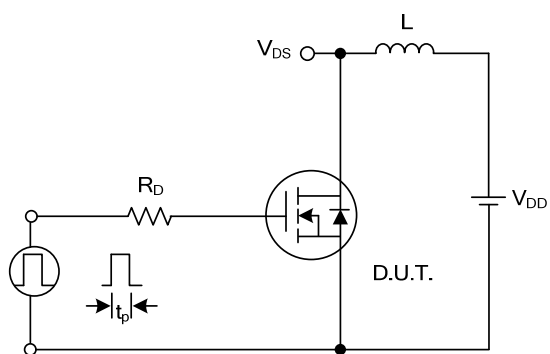
Switching Waveforms



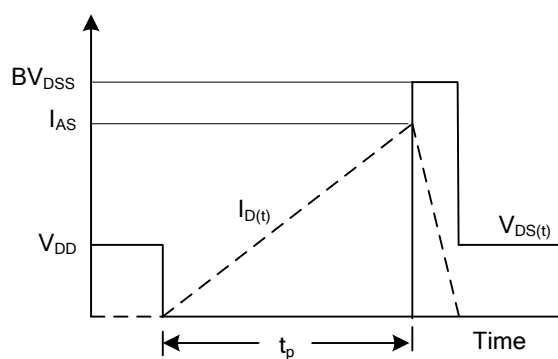
Gate Charge Test Circuit



Gate Charge Waveform

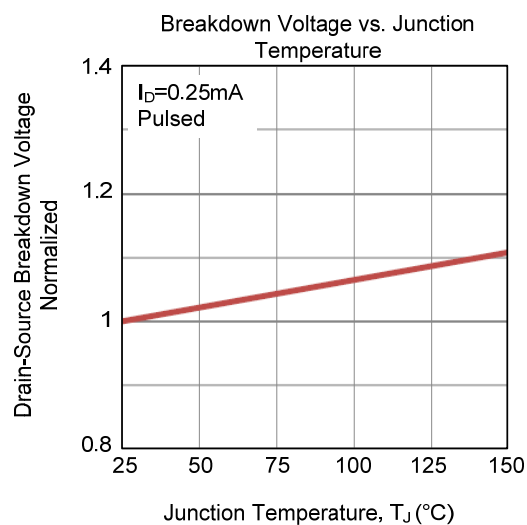
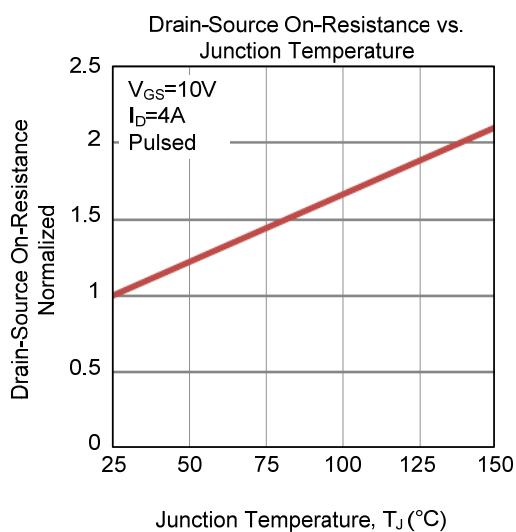
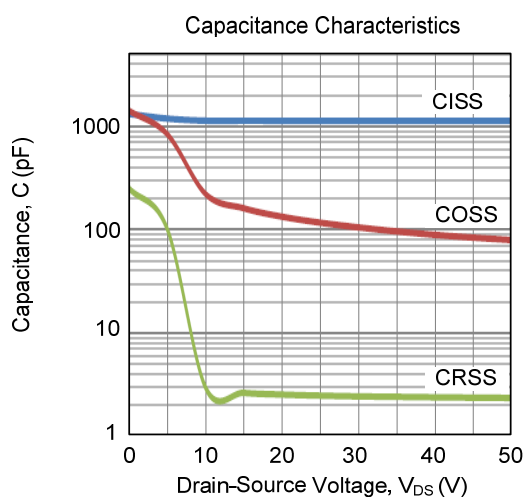
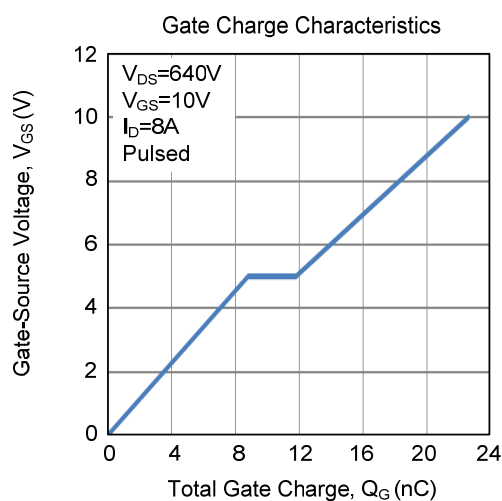
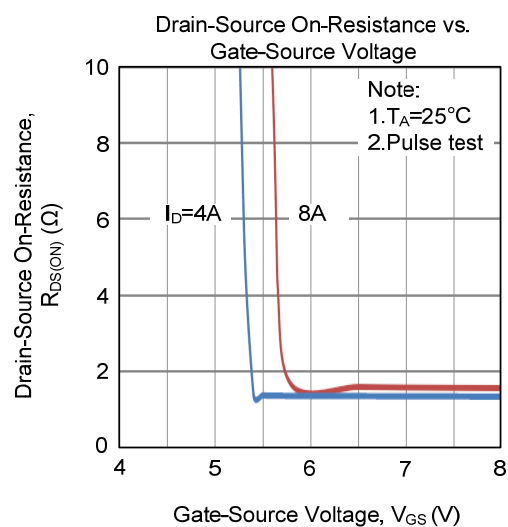
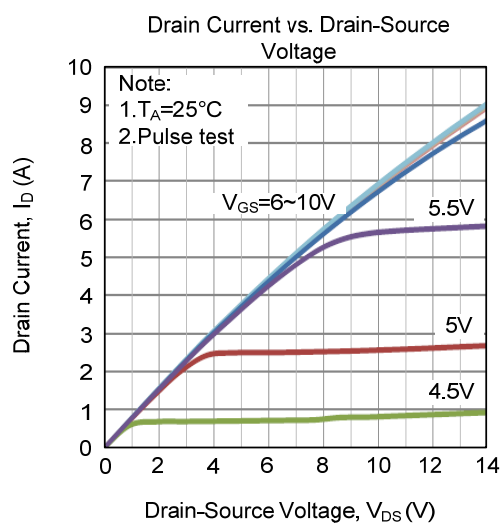


Unclamped Inductive Switching Test Circuit

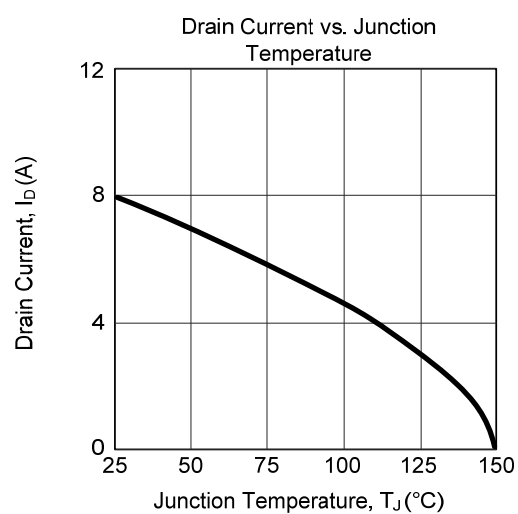
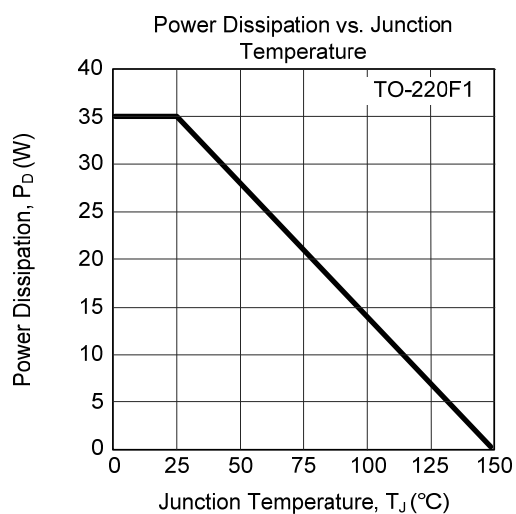
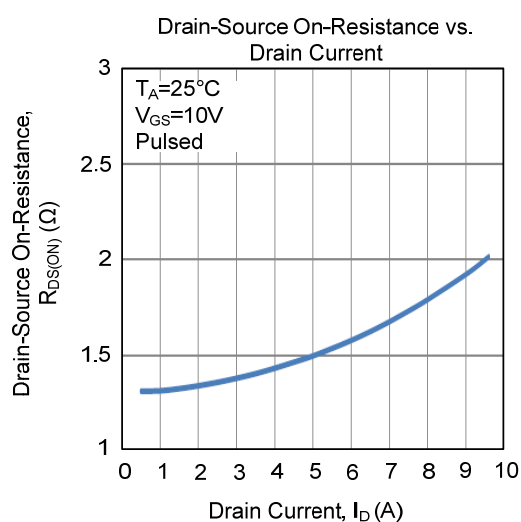
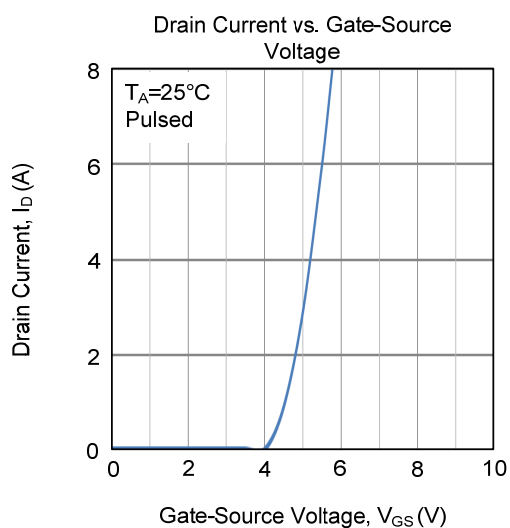
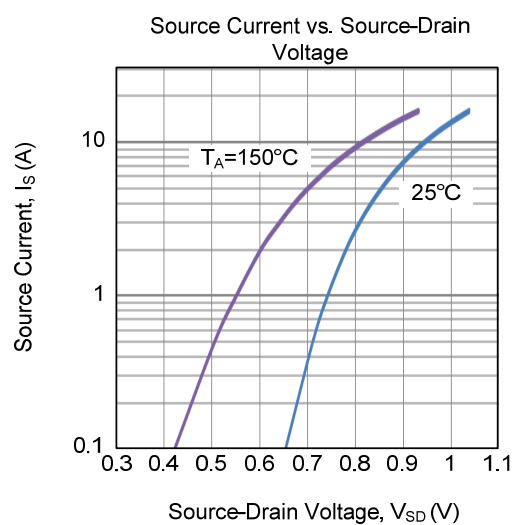
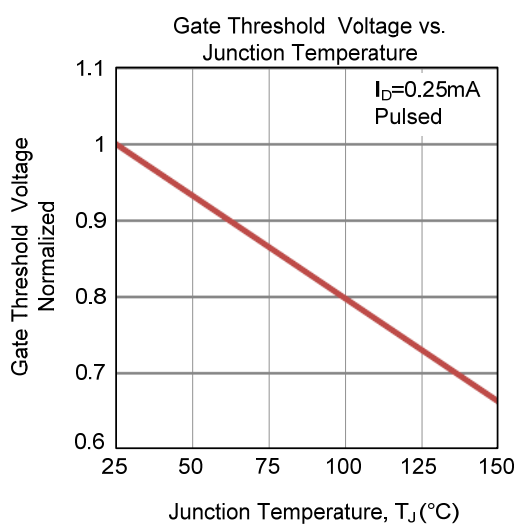


Unclamped Inductive Switching Waveforms

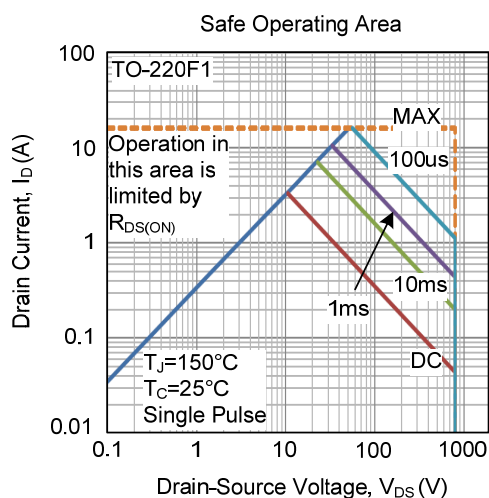
TYPICAL CHARACTERISTICS



■ TYPICAL CHARACTERISTICS (Cont.)



TYPICAL CHARACTERISTICS (Cont.)



UTC assumes no responsibility for equipment failures that result from using products at values that exceed, even momentarily, rated values (such as maximum ratings, operating condition ranges, or other parameters) listed in products specifications of any and all UTC products described or contained herein. UTC products are not designed for use in life support appliances, devices or systems where malfunction of these products can be reasonably expected to result in personal injury. Reproduction in whole or in part is prohibited without the prior written consent of the copyright owner. UTC reserves the right to make changes to information published in this document, including without limitation specifications and product descriptions, at any time and without notice. This document supersedes and replaces all information supplied prior to the publication hereof.